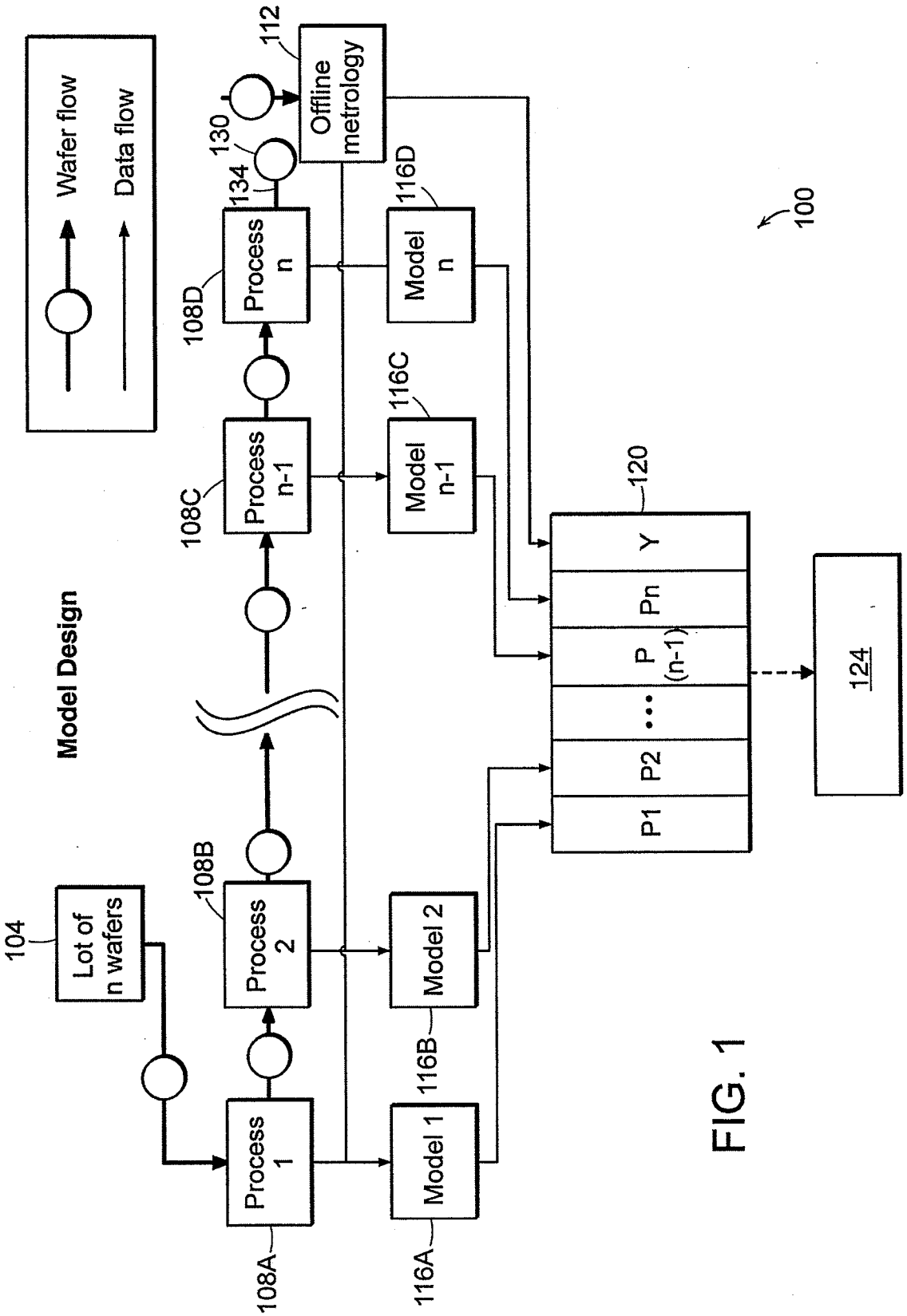

Wafer flow
Data flow
Model Design
104
Lot of n wafers
108A
Process 1
116A
Model 1
108B
Process 2
116B
Model 2
108C
Process n-1
116C
Model n-1
108D
Process n
116D
Model n
130
134
112
Offline metrology
120
P1
P2
P (n-1)
Pn
Y
124
100

FIG. 1

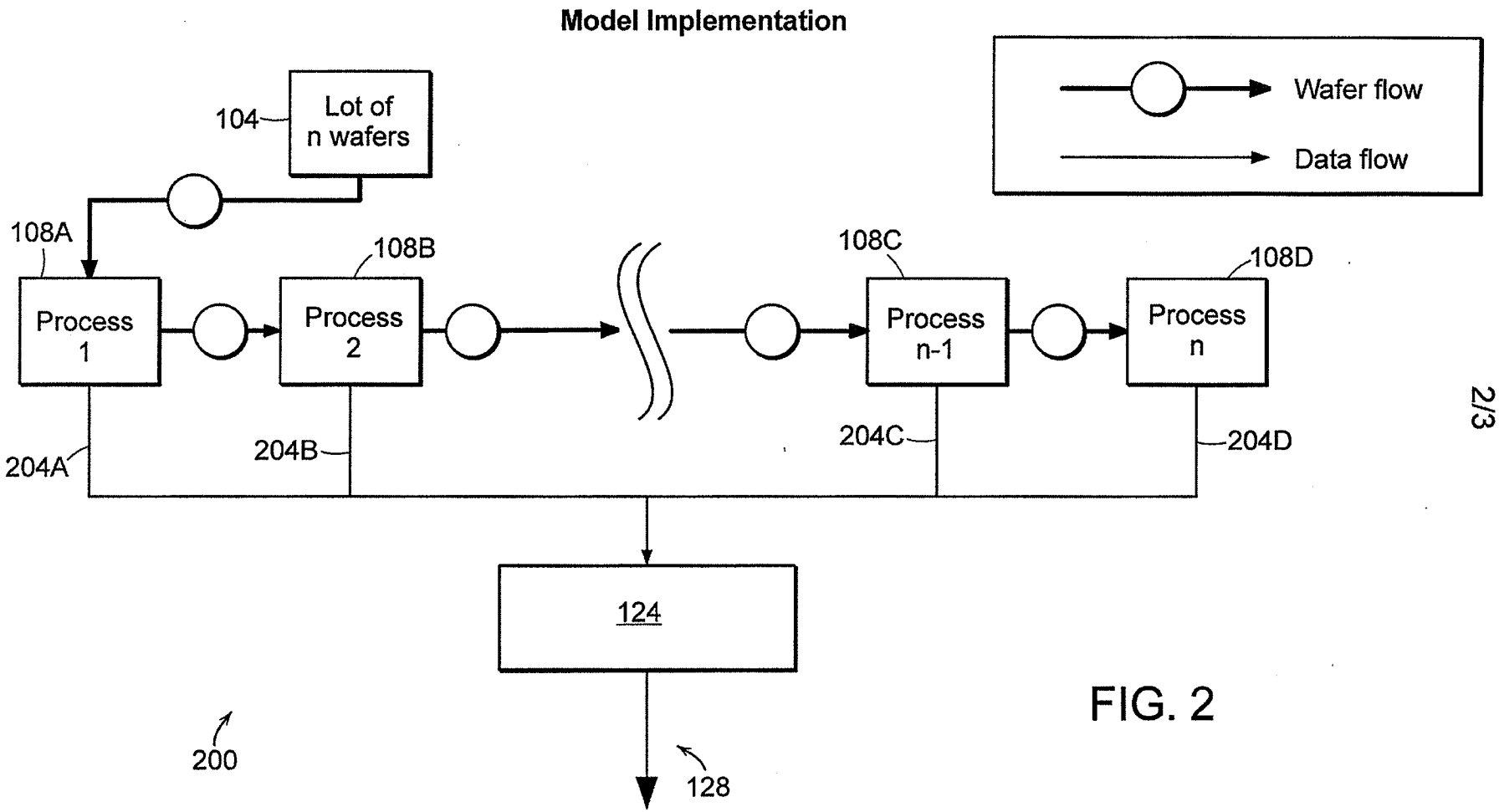

Model Implementation
Wafer flow
Data flow
104
Lot of
n wafers
108A
108B
108C
108D
Process
1
Process
2
Process
n-1
Process
n
204A
204B
204C
204D
124
200
128

FIG. 2

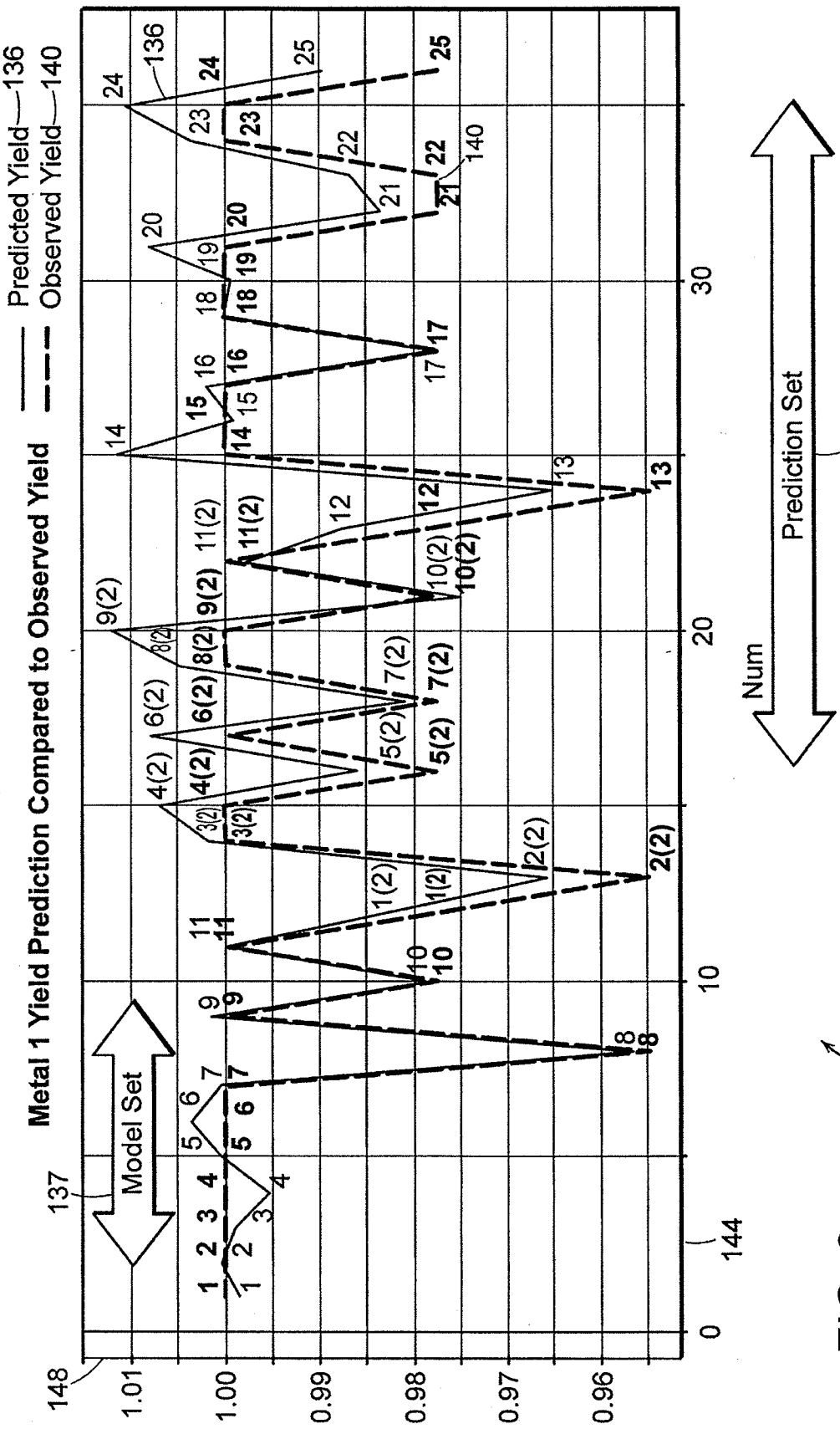

Metal 1 Yield Prediction Compared to Observed Yield
Predicted Yield 136
Observed Yield 140
Model Set
137
Num
Prediction Set
138
132
144
148
1.01
1.00
0.99
0.98
0.97
0.96
0
10
20
30

FIG. 3